

<b>Notice of References Cited</b>	Application/Control No. 10/626,206		Applicant(s)/Patent Under Reexamination TSUGIWA, NAOMITSU	
	Examiner Christian E. Rendón		Art Unit 3714	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0133523	09-2002	Ambler et al.	707/536
*	B	US-5,618,238	04-1997	Kruse et al.	473/70
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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